



1st MONOLITH Workshop on silicon sensors for timing and their applications Genève, 5-6 Sept. 2022

FBK LGAD Technology for fast timing

FBK LGAD group: A. Bisht, G. Borghi, M. Boscardin, M. Centis Vignali, F. Ficorella, O. Hammad Ali, G. Paternoster

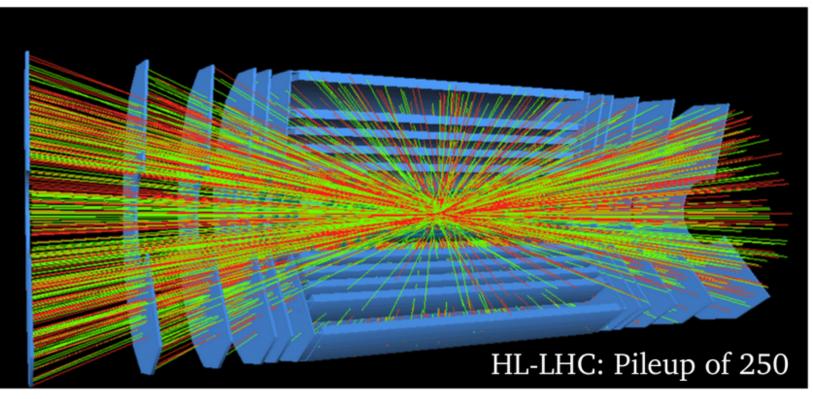
> **UFSD** group INFN Torino, Univ. of Turin, Univ. of Piemonte Orient, Univ. of Trento, FBK Trento, Univ. of California at Santa Cruz.

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Introduction and Motivation

- LGAD Technology developed at FBK since 2015
- Developed together with INFN Turin and University Trento for 4d-tracking
- More than 15 batches produced since 2015

Motivation





- - bunch crossing
 - events
- - Timing resolution: 30 ps (rms) -
 - Low spatial granularity: ~1 mm (timing information assigned to the track)







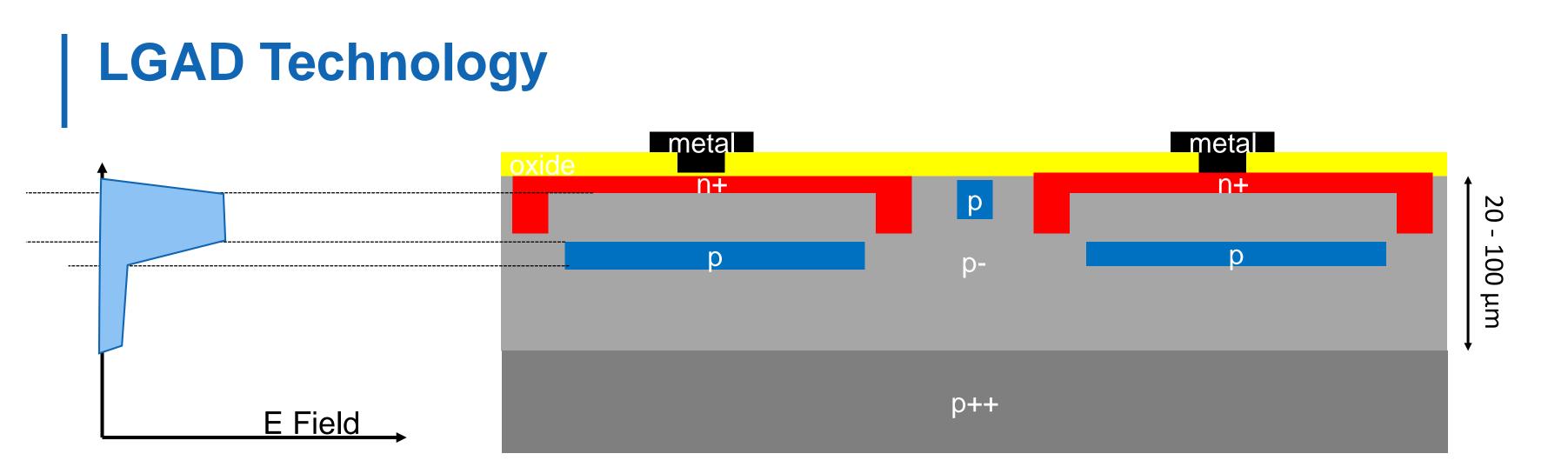
- High Luminosity LHC (HL-LHC, operational in 2026):

Luminosity: $\times 5$ compared to LHC \rightarrow 150-200 events per

Timing and spatial resolution of standard silicon tracking sensors not sufficient: 10-15% of vertexes composed of 2

Requirements for silicon timing detectors in HL-LHC:

- High radiation hardness: > $1 \cdot 10^{15} n_{eq} \cdot cm^{-2}$



Technological features

- Silicon detectors with internal charge multiplication
- Gain: 10-20
- Gain layer provides high-field region •
- Depleted thickness: 20 100 µm (epi or Si-Si wafers)

- sensor
- lacksquare
- lacksquare



Main functionalities

Time resolution 30 ps with thin 50 μ m

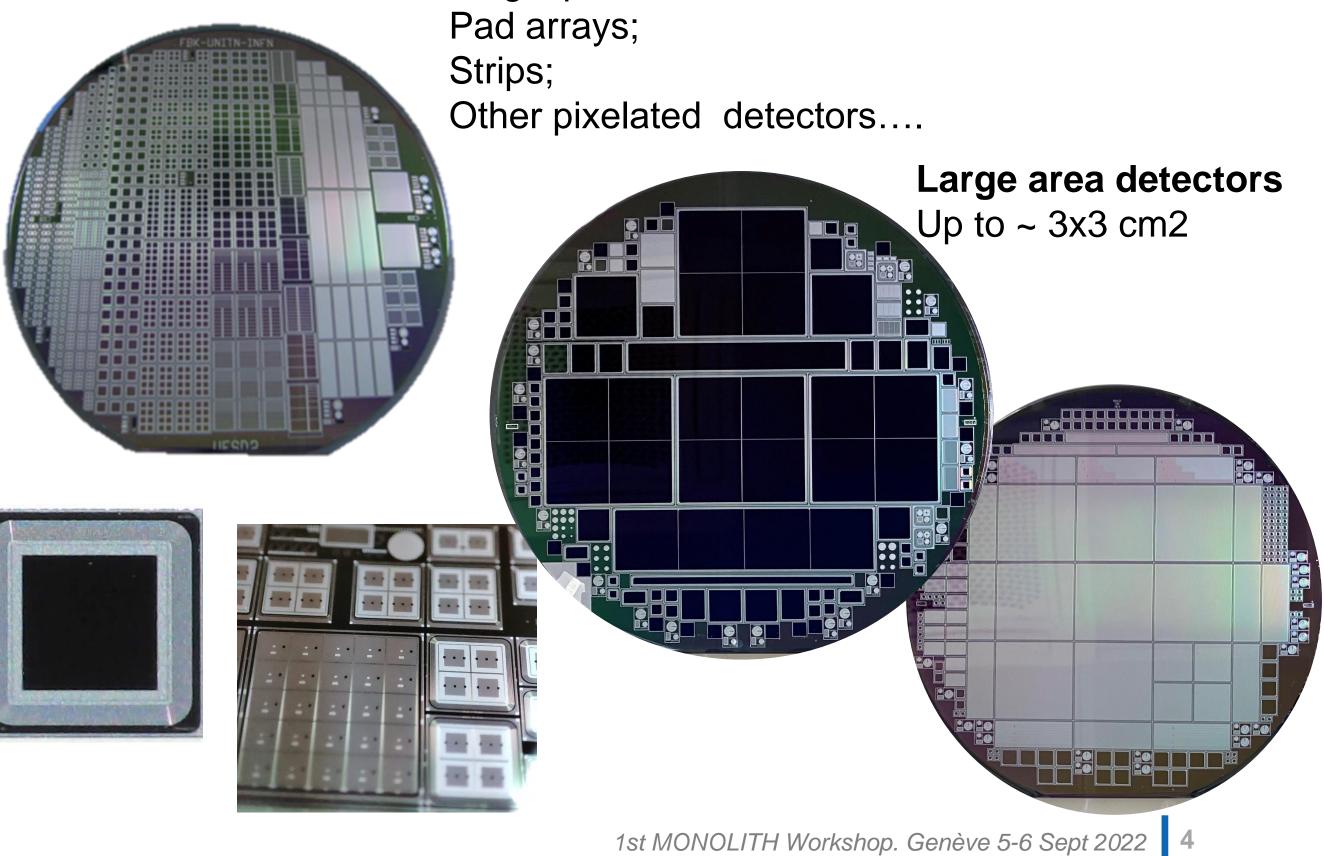
Improve SNR of the system (when the sensor shot noise is not dominating) Low Noise and power consumption

LGAD Fabrication Technology

- Fabricated on 6 inches Wafers
- Custom CMOS-like Technology
- Fabricated in the FBK internal facility (ISO 9001:2015 certified)



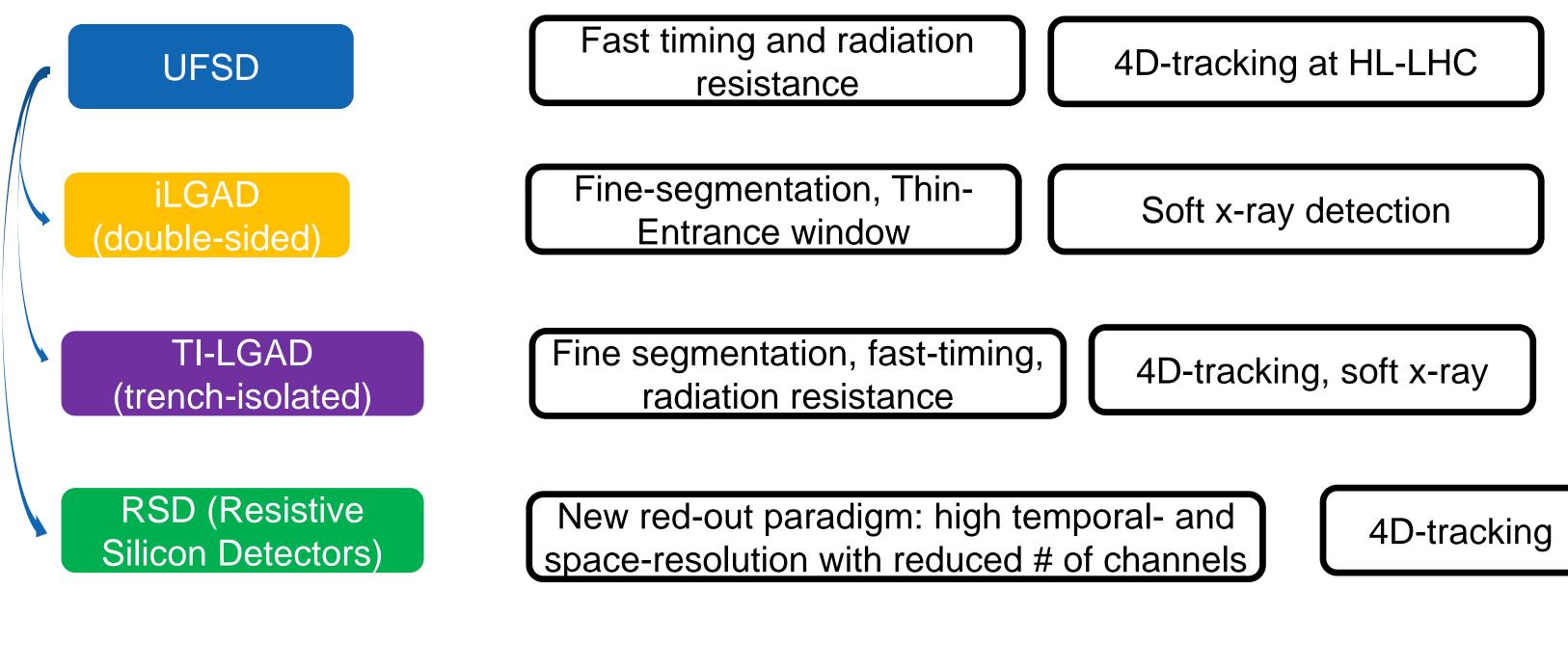




- Single pads,

FBK LGAD Technology Roadmap

Different designs, optimized for different applications

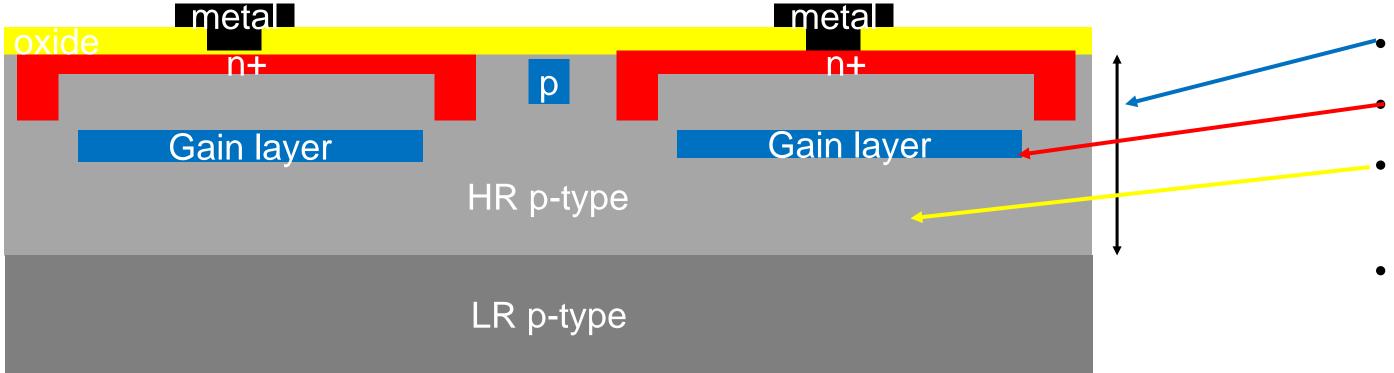






UFSD: Recipe for fast timing

Key factors governing time resolution of LGADs. Both design & technology





Thickness

Gain

- Drift velocity of e⁻ in the bulk
- Pad geometry (weighing field)

Gain

- Gain depends on GL dose and Bias Voltage
- High Gain reduces the jitter
- At too high gain the time resolution is dominated by Landau noise

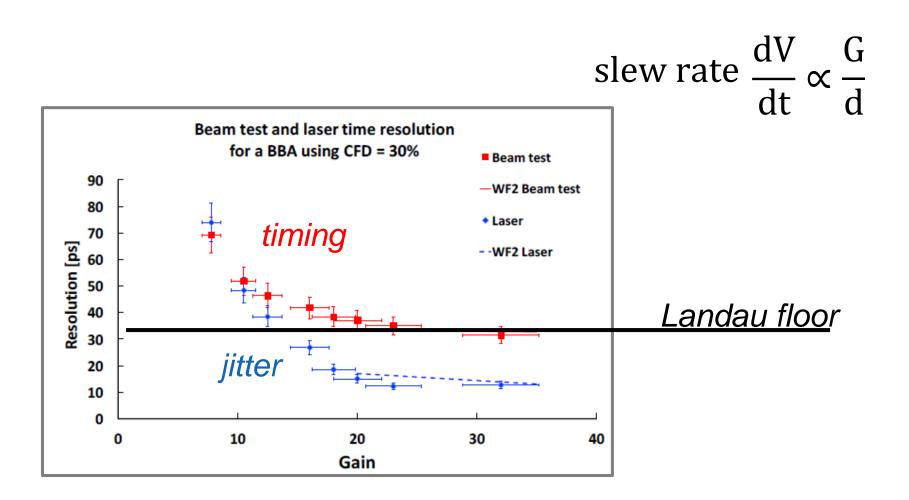
Rule: use the minimum gain that allows reaching the minimum value in time resolution

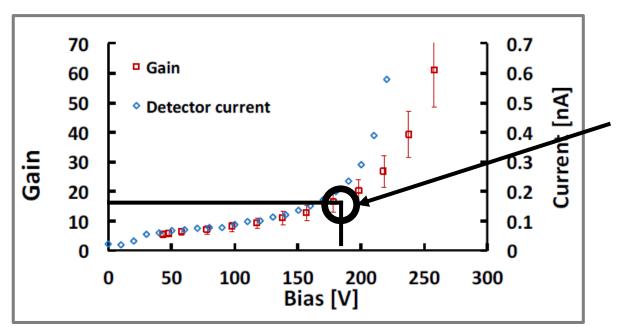
Bulk E_{field}

- Target gain should be reached at a Bias where the e-velocity in the bulk is saturated (E > 3e4 V/cm)
- For 50 µm the target is G~10 at V > 200 Volts



Sadrozinski et al 2018 Rep. Prog. Phys. **81** 026101 1st MONOLITH Workshop. Genève 5-6 Sept 2022





Working point

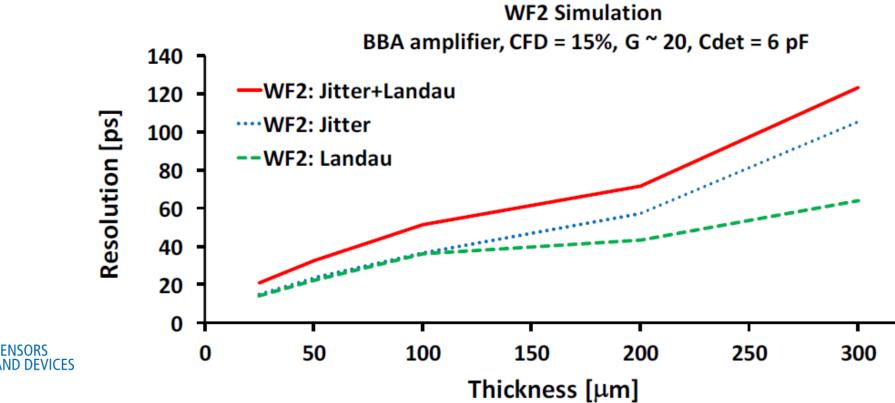
Thickness

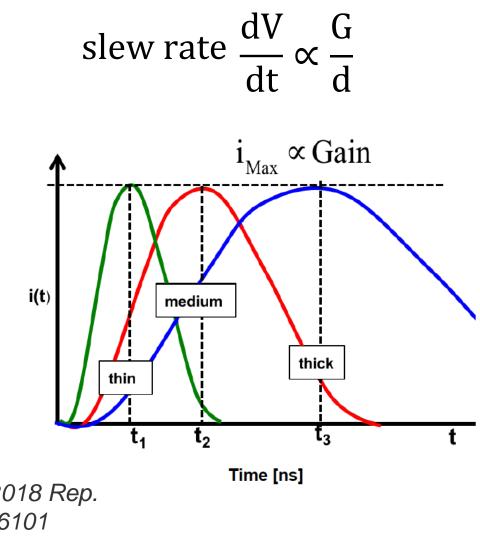
Reducing Thickness ->

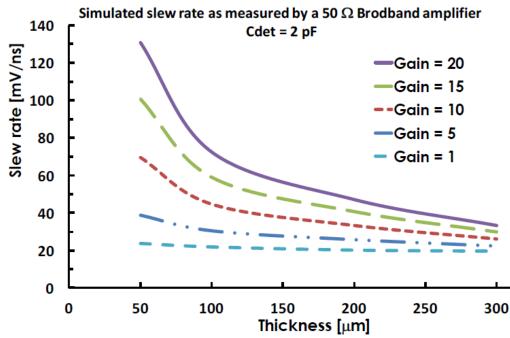
Higher slew-rate Lower Landau and Time-walk High capacitance Less radiation resistance (SEB)

Trade off ~ 50 um

Sadrozinski et al 2018 Rep. Prog. Phys. **81** 026101







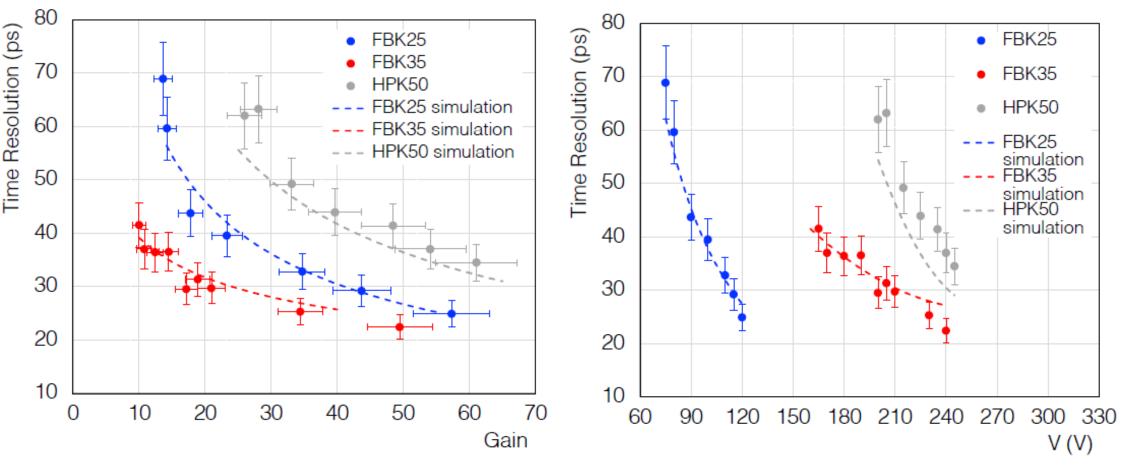


Latest test with ultra-thin LGADs 35 μm and 25 μm

F. Carnesecchi, arXiv:2208.05717



- Ultra-thin sensors produced at FBK (EXFLU project)
- Characterized at INFN Bologna, INFN Turin and CERN





Wafers from eXFlu0 production

- 35µm thick LGADs approach 20ps time resolution (mainly thanks to Landau noise reduction)
- No further improvement moving to 25 µm. Possible causes:
 - higher substrate doping (not saturated electrons velocity in the bulk)
 - Higher noise of the sample

Initial Acceptor removal

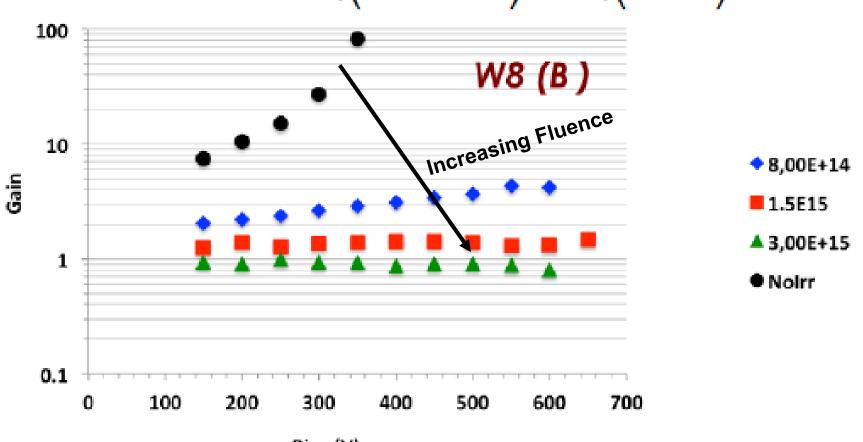
- During irradiation the Gain of LGADs is reduced
- The mechanism can be explained with a reduction of the acceptor concentration in the Gain Layer

$$N_A(\emptyset) = N_A(\mathbf{0}) \ e^{-c\emptyset}$$

- It is possible to partially compensate the gainloss by increasing the bias voltage
- Gain is completely lost after 1e15 neq/cm²

Possible microscopic mechanism: Boron de-activation due to Si interstitial

> $Si_i + B_s \rightarrow B_i$ $B_i + O_i \rightarrow B_iO_i$ (donor-like)

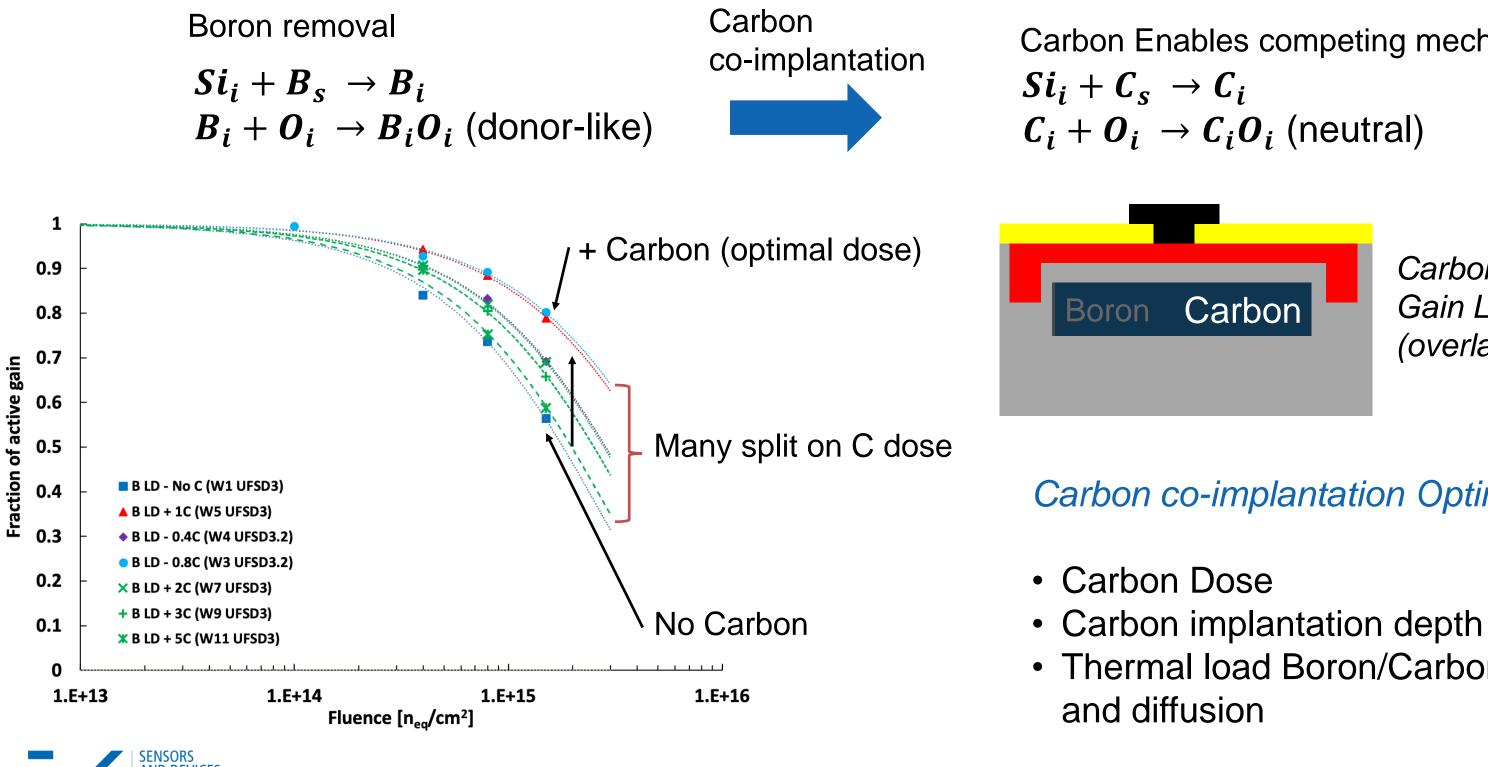




[R. Arcidiacono TREDI2018] Gain = Q(LGAD) / Q(PiN)

Bias (V)

Carbon Co-implantation for acceptor removal mitigation





Carbon Enables competing mechanism

$$\rightarrow C_i$$

 $\rightarrow C_i O_i$ (neutral)

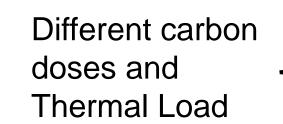
Carbon implanted only in the Gain Layer at the same depth (overlapping to Boron)

Carbon co-implantation Optimization

Thermal load Boron/Carbon for activation

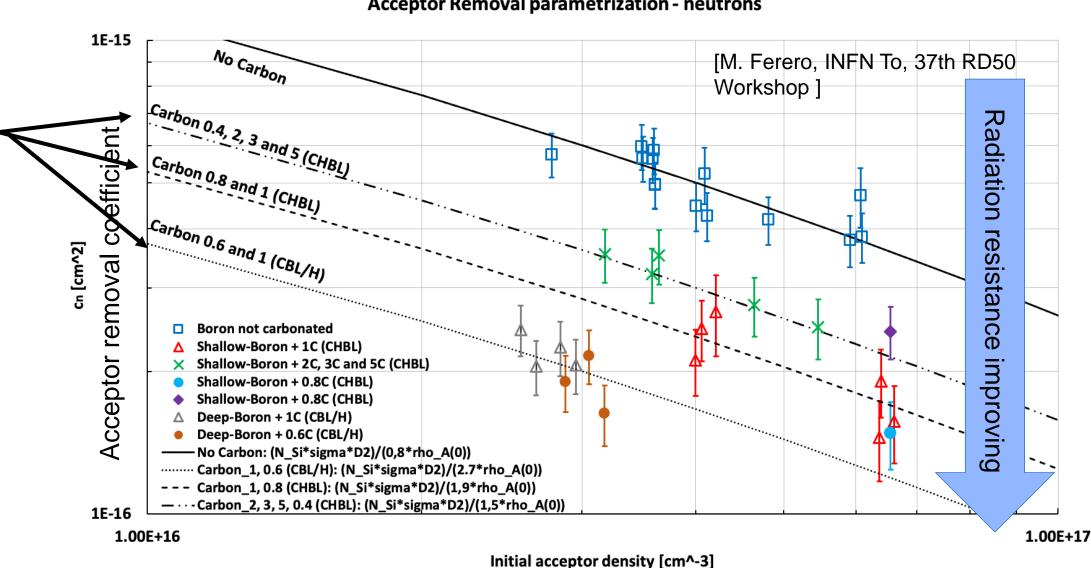
Carbon co-implantation for acceptor removal mitigation

 $\boldsymbol{c} = \boldsymbol{c}(\boldsymbol{N}_{\boldsymbol{A}}(\boldsymbol{0}))$ $N_A(\emptyset) = N_A(0) \ e^{-c\emptyset}$



Recipe for high radiation resistance

- 1. Using optimized Carbon dose
- 2. Increase boron density (w/o increasing the gain too much)





Acceptor Removal parametrization - neutrons

Higher initial boron Density

Gain layer optimization

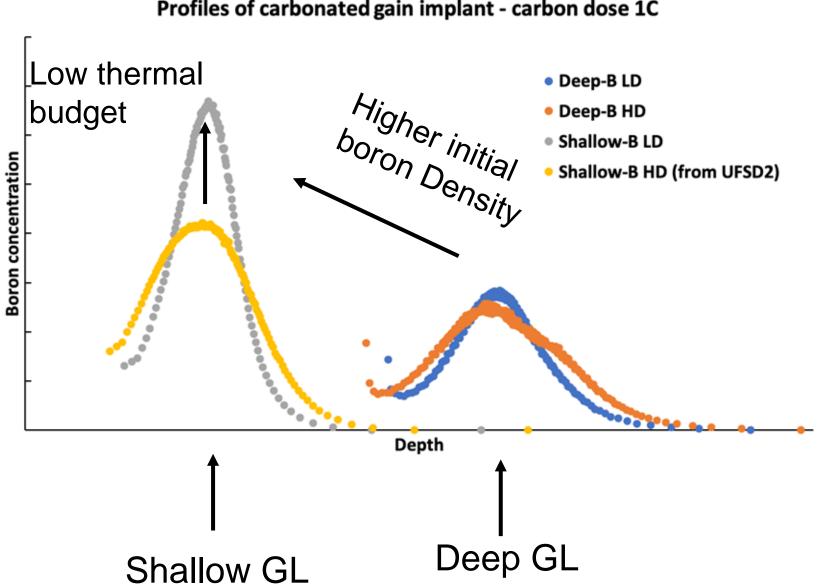
Boron depth: Shallow (~1um) or Deep Thermal diffusion (low or high)

Higher Boron concentration -> lower c factor

- Shallow B implant (more dose for the same gain)
- Narrower (low diffused) B profiles •

Disadvantages of a Shallow gain layer:

• Worst gain recovery than deep-gain implant, using external bias



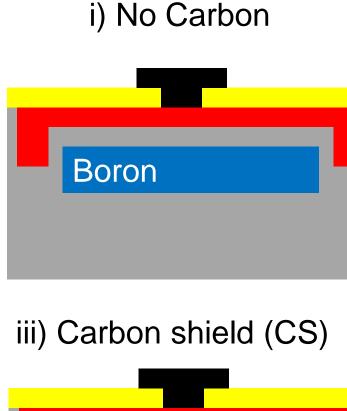


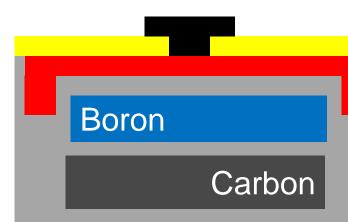
Profiles of carbonated gain implant - carbon dose 1C

Carbon Co-implantation for acceptor removal mitigation

- Shifting (or adding) an additional Carbon implant deeper than the Gain Layer (Carbon shield)
- More tests are ongoing...

First tests on GLC + CS show a further decreasing of the c factor of \sim 20%.

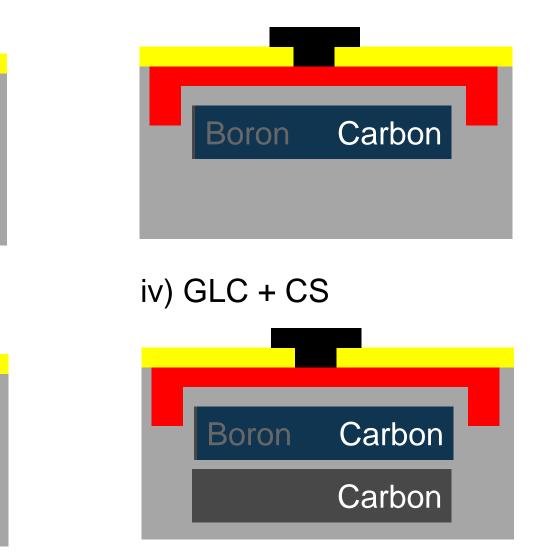


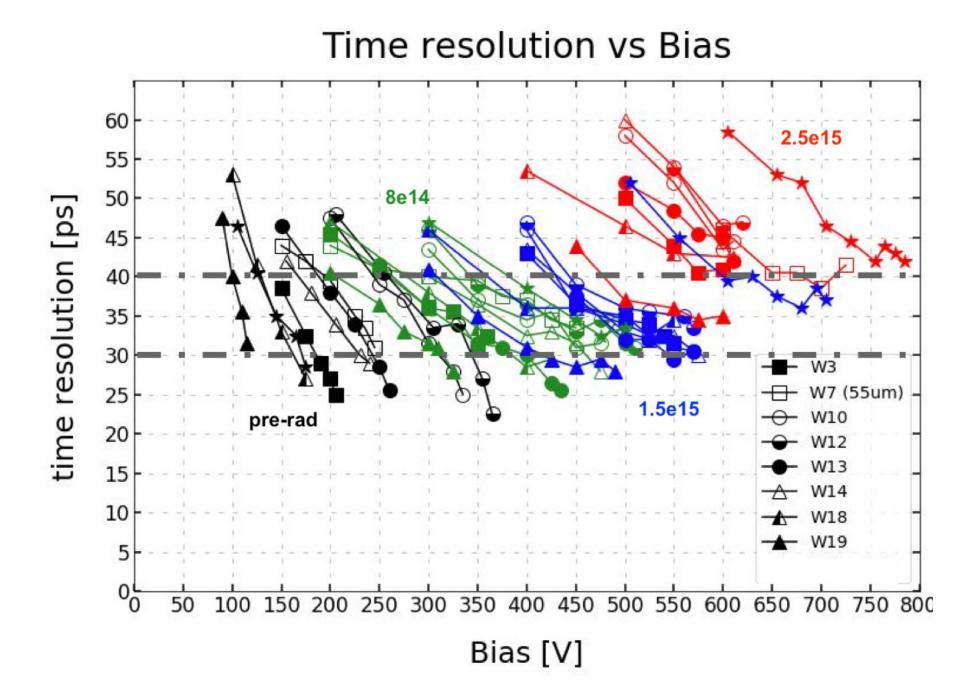


(the right place to add Carbon has still to be understood...)



ii) Carbon in the Gain Layer (GLC)





Demonstrated radiation resistance and time resolution for HL-LHC



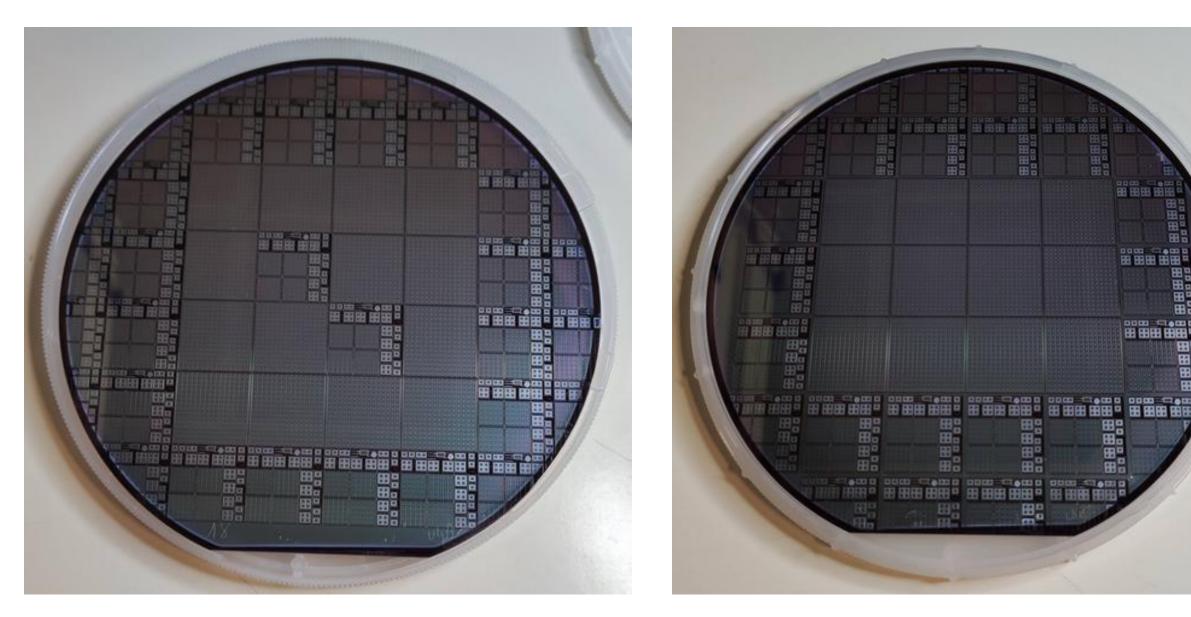
Time resolution

< 30 ps up to 1e15 neq/cm² $< 40 \text{ ps up to } 2.5e15 \text{ neq/cm}^2$

Production qualification

ATLAS - HGTD

CMS - ETL

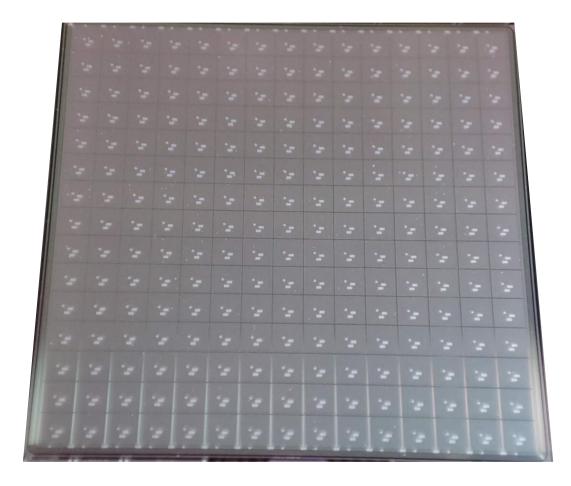


UFSD 4 batch for final sensor qualification



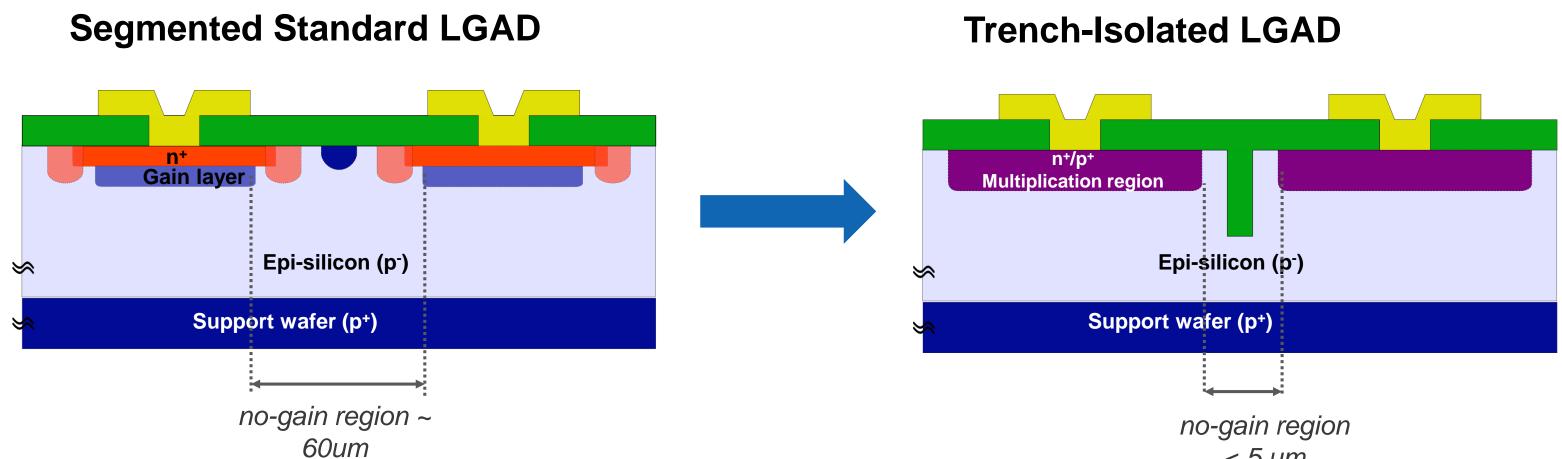
• Full sensors ~ 2 x 2 cm²

- 15 x 15 and 16 x 16 arrays
- 1.3 mm² pads



Novel LGAD schemes for fine-segmentation

Trench Isolated - LGAD Technology



- No-gain region at the pixel border due to isolation and termination structures: JTE and p-stop
- Dead distance for charge multiplication
- ~ 40 80 µm ND DEVICES

< 5 um

JTE and p-stop are replaced by a single trench (< 1 um wide) Trenches act as a drift/diffusion barrier for electrons and isolate the pixels.



Novel LGAD schemes for fine-segmentation

Trench Isolated - LGAD Technology

Pixels

 $55 \times 55 \ \mu m^2$ (Medipix/Timepix) **FF > 80%**

Inter-pad distance

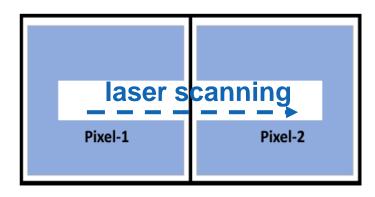
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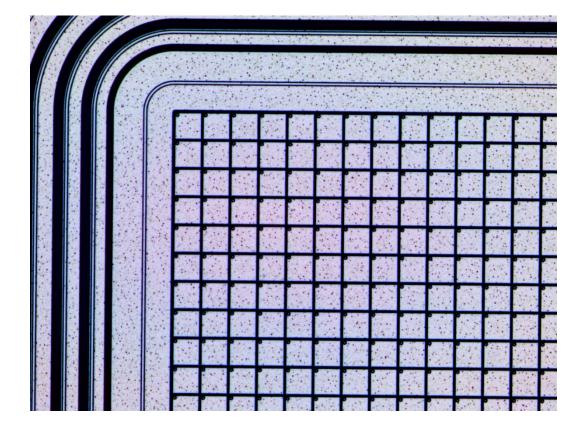
0.6

0.4

0.2

Interpixel distance in the range 2-10 um (depending on the layout split)

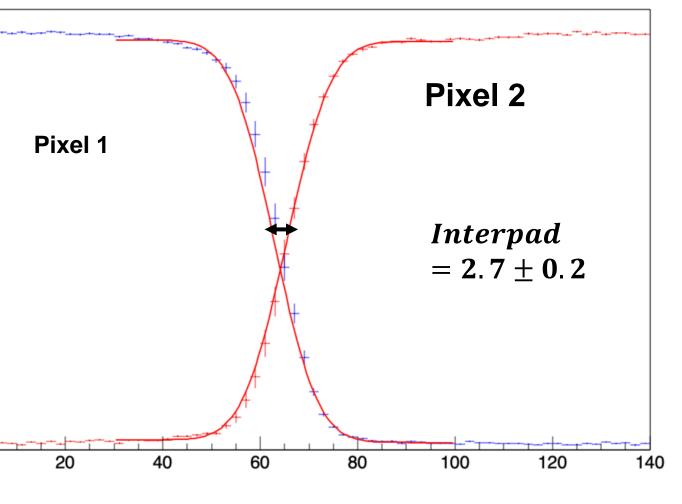






Measured with TCT setup (red laser)

Measured at INFN TO (courtesy of M. Ferrero)



Novel LGAD schemes for fine-segmentation

Trench Isolated - LGAD Technology

Pixels

55 × 55 μm² (Medipix/Timepix) **FF > 80%**

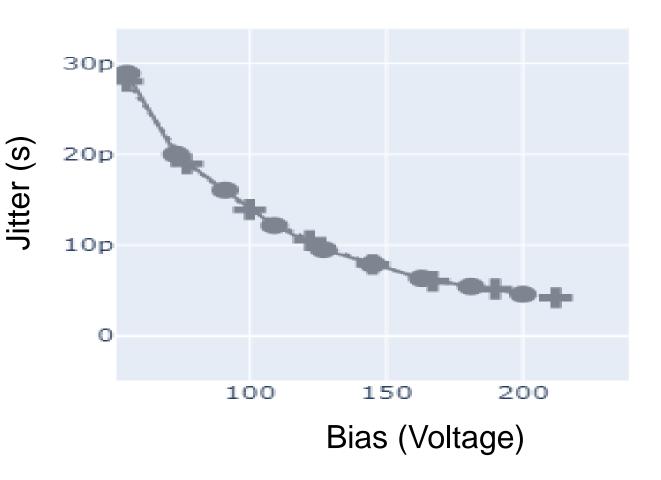
Time Resolution (jitter) Measured with TCT setup (red laser)

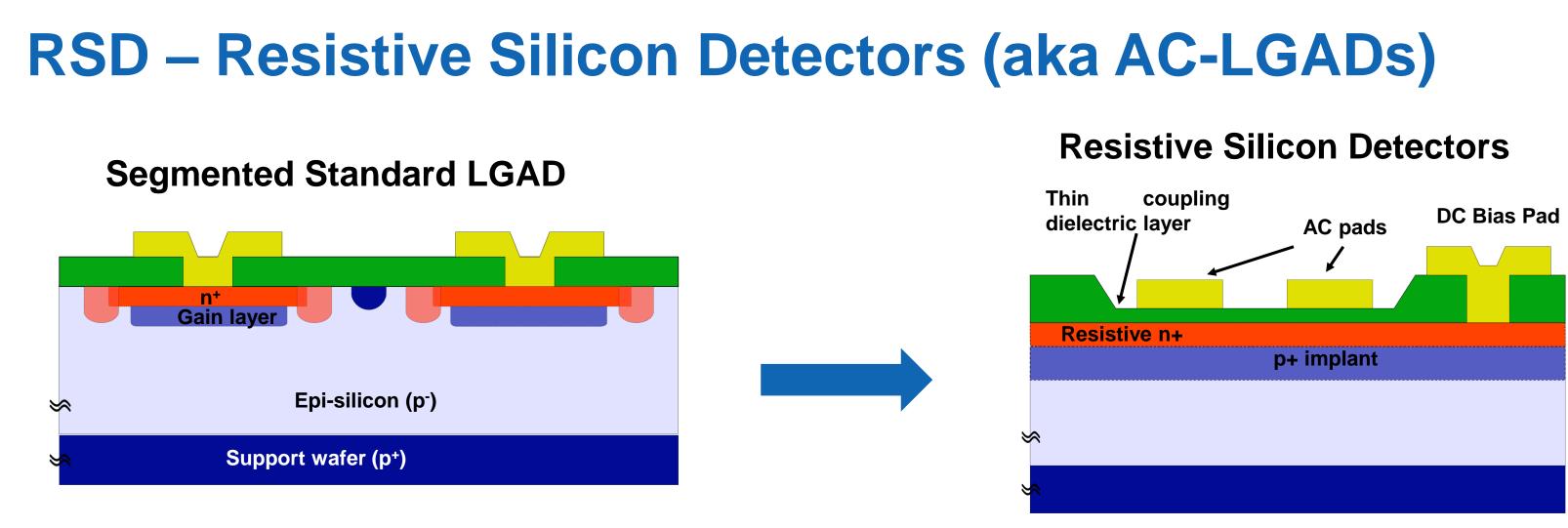
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- Not-degradated time resolution wrt standard LGADs
- Time resolution (laser setup) < 10 ps



M. Senger – VCI 2022





Main Technological Features

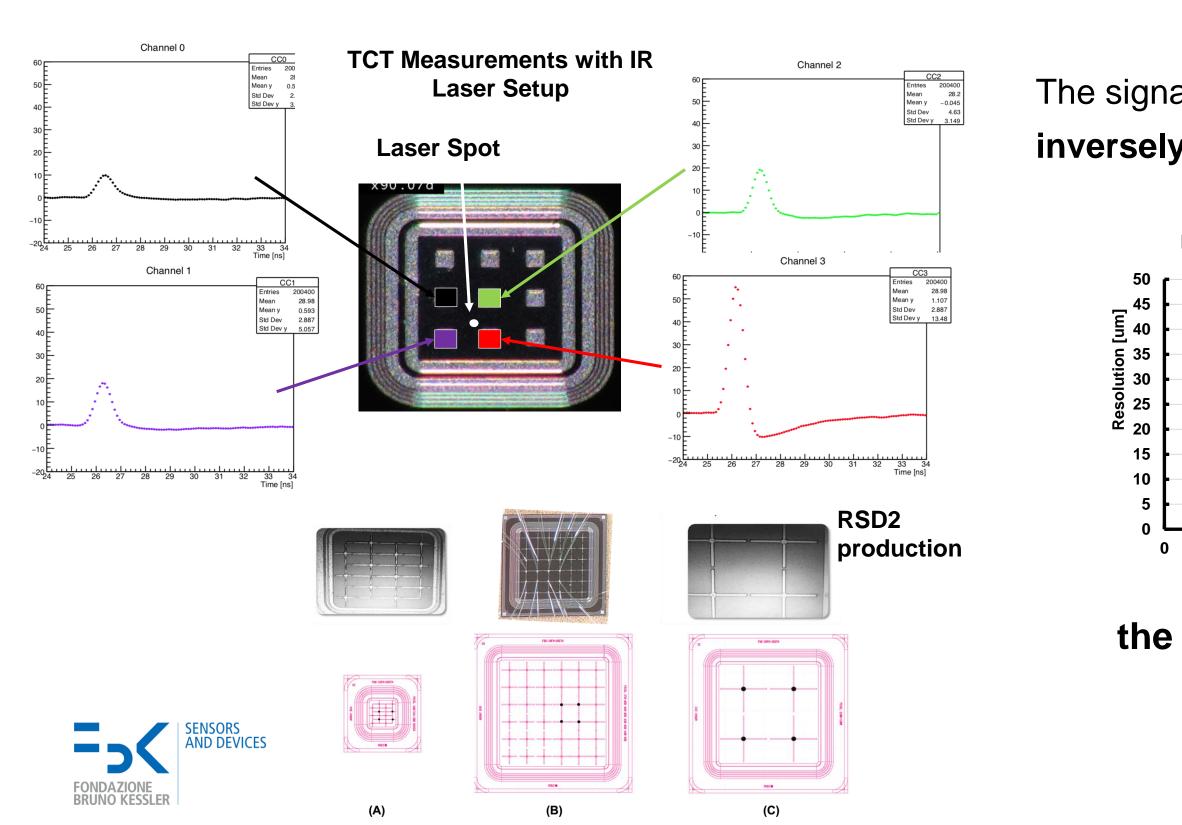
- Not-segmented p-gain implant
- Resistive n+ implant
- AC Metal pads



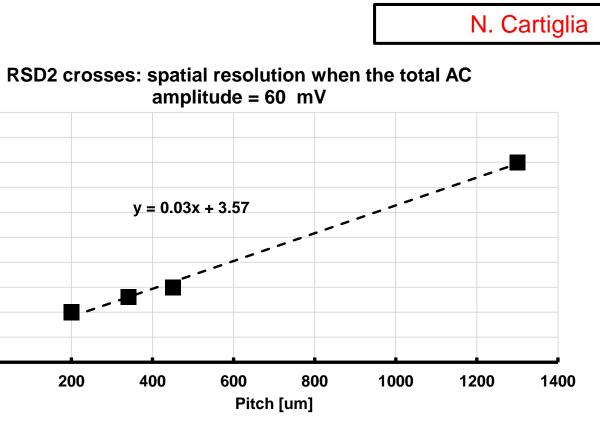
RSD is not just an LGAD with AC-pads. It is a different way to read-out the signal and to segment the sensor

RSD – Resistive Silicon Detectors (aka AC-LGADs)

How does it works



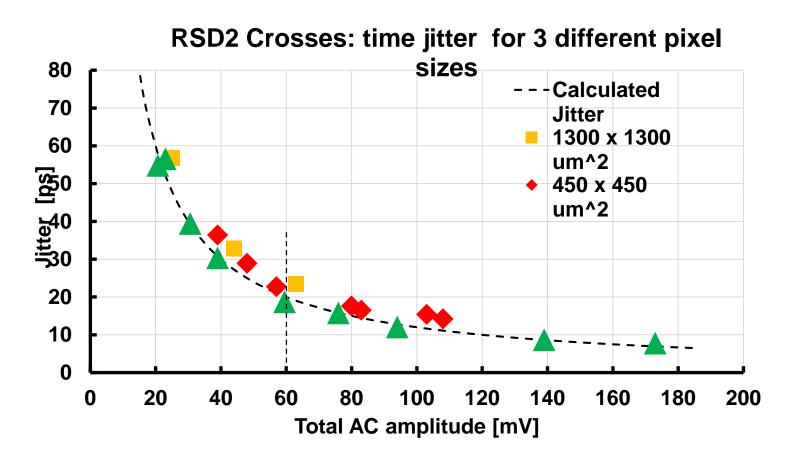
The signal spreads on several pads, with **amplitude inversely proportional to the hit distance**

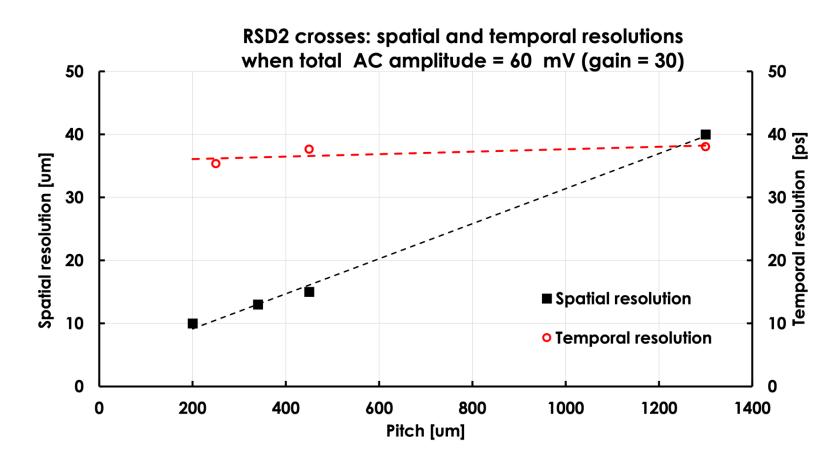


the resolution is 3% of the pixel size

RSD – Resistive Silicon Detectors (aka AC-LGADs)

Time resolution





The temporal resolution does not depend on the pize size, only on the total amplitude.

(total amplitude = sum of the amplitudes of the 4 readout electrodes at the pixel corner)



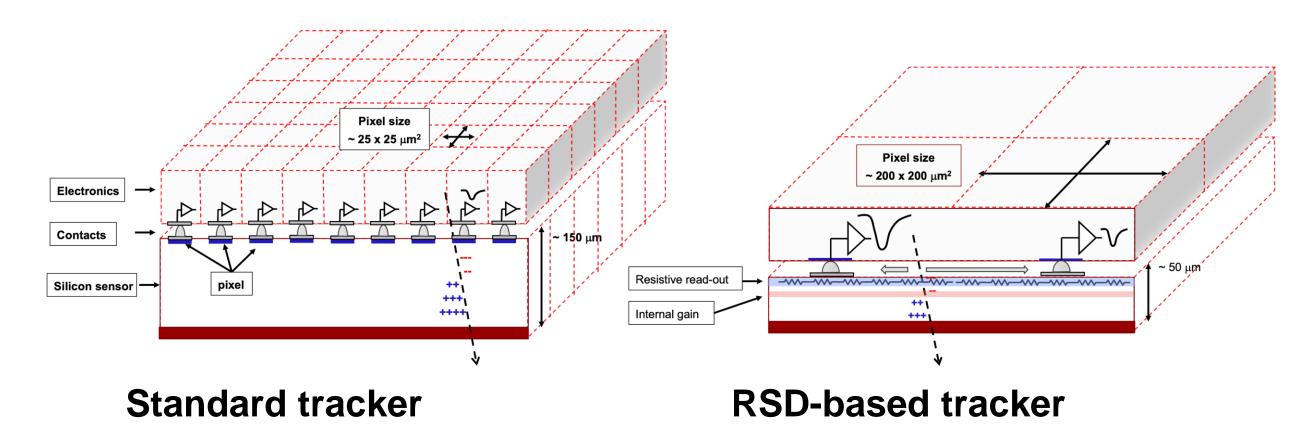
RSD2 crosse overall result:

- Spatial resolution ~ 3% pitch size
- Temporal resolution ~ 35 ps, regardless of
 - pitch size

N. Cartiglia

RSD – Resistive Silicon Detectors (aka AC-LGADs)

Final GOAL



The design of a tracker based on RSD:

It delivers ~ 30 ps temporal resolution and excellent spatial resolution with large pixels

- For the same spatial resolution, RSD trackers use 50-100 fewer pixels •
- The electronic circuitry can be easily accommodated •
- The power consumption is much lower;



Conclusions

- In the last years FBK developed LGADs technology for 4D-tracking ullet
- Last developments in LGAD lead to time resolution ~30ps up to fluences of 2.5e15 neq, ulletmainly thanks to the using of thin substrates and initial acceptor removal mitigation
- The radiation resistance can be further increased by optimizing Carbon co-implantation or ulletdopant co-implantation
- The new TI-LGAD technology preserves the time resolution of LGADs scaling down the \bullet pixel size to few tens of microns.
- RSD technology can combine the 30ps time resolution, few microns space resolution and radiation hardness with a reduced number of read-out channels.





Thank you for your attention

Acknowledgements

- Part of the work has been performed in the framework of RD50
- Some batches have been produced in the framework of convenzione **INFN/FBK**
- Horizon 2020, grant UFSD669529
- Progetto PRIN2017, MIUR, 4DInSide, Prin2017
- Progetto FARE, MIUR, R165xr8frt_fare
- Dipartimenti di Eccellenza, Torino Physics Dep. (ex L. 232/2016, art. 1, cc. 314, 337)

UFSD group **INFN Torino, Univ. of Turin, Univ. of Piemonte Orient, Univ. of** Trento, FBK Trento, Univ. of California at Santa Cruz.

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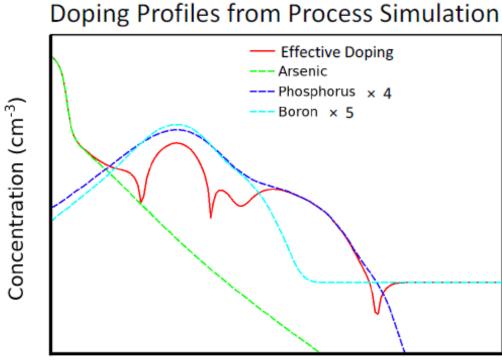
Radiation Hardening at extreme fluences

Psphorous/Boron co-doping

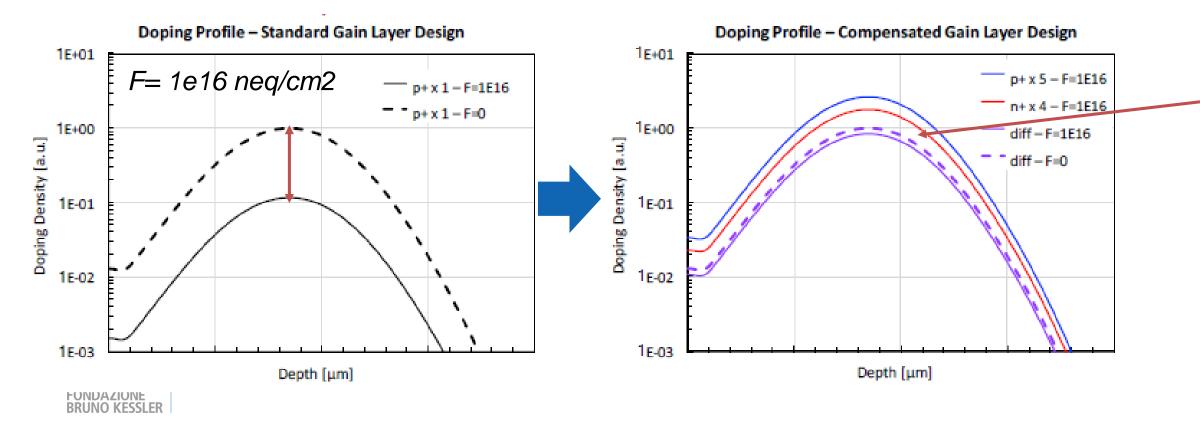


eXFlu project (V. Sola, INFN To)

GOAL: operate LGADs at fluence > 10^{16} neq/cm









Gain layer is obtained by co-implanting Boron and Phosphorous

1*B -> 5*B + 4*Ph

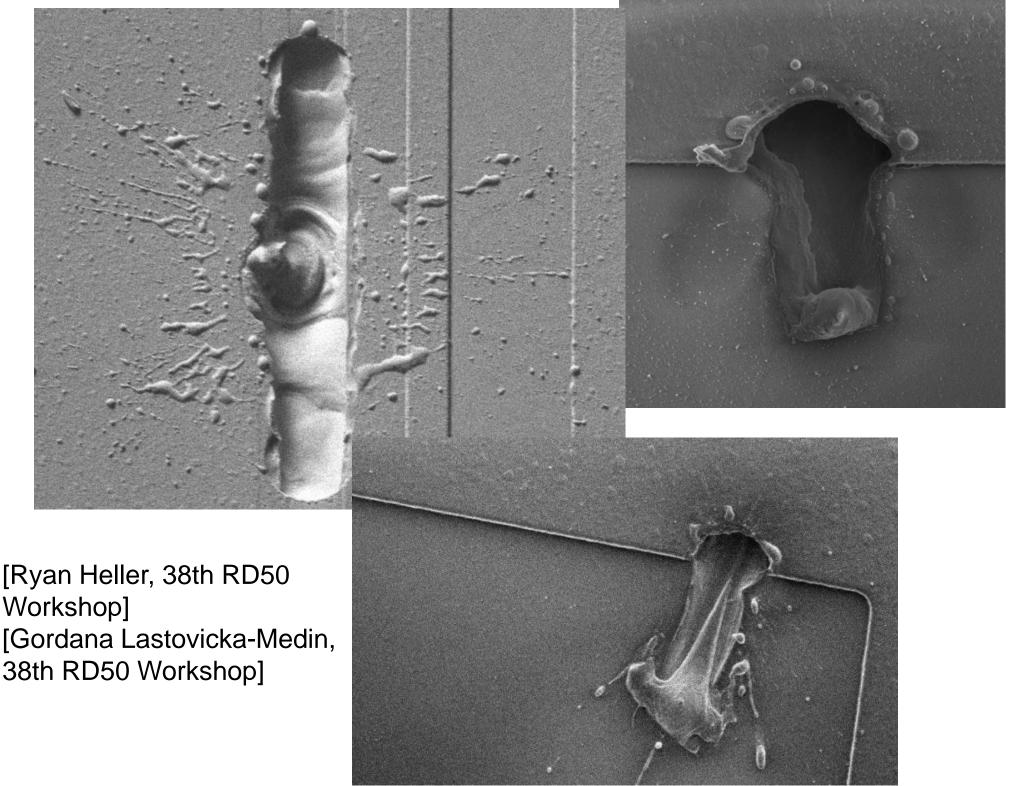
- No acceptor removal after F=1e16 neq/cm2
- It works under the assumption ($c_A \approx c_B$)
- Production to be completed in October 2022

LGAD – Radiation hardness

Thickness

SEB = Single Event Burnout

- Death of highly irradiated LGADs at test beam
- Probably due to a rare, large ionization events • producing large current in narrow path
- Mortality is function of sensor thickness and voltage only (Gain is not necessary for death mechanism)
- Fatal voltage: > 600V for 50 um Sensors •
- Fatal Voltage becomes lower for thinner sensors

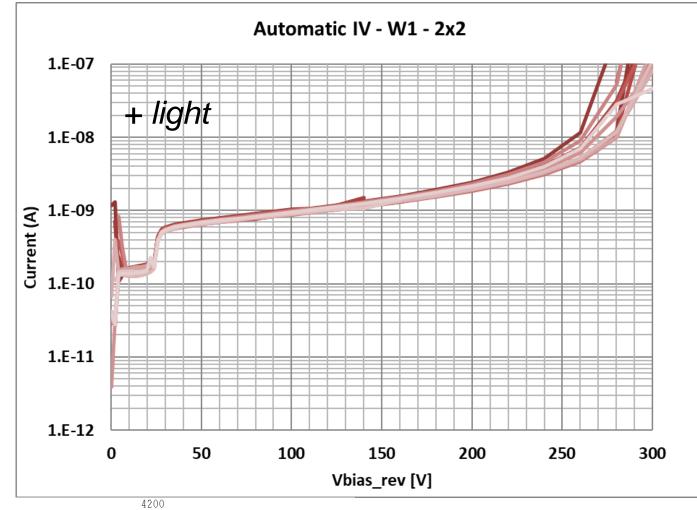


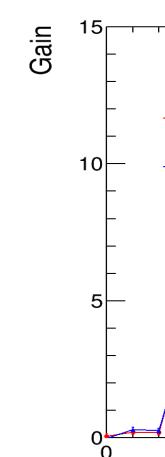
[Ryan Heller, 38th RD50 Workshop] 38th RD50 Workshop]

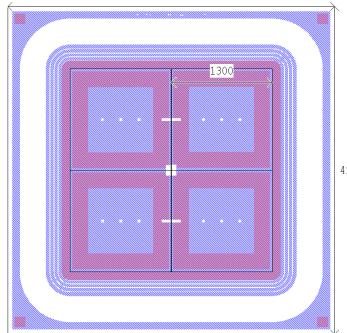


TI-LGAD Production Batch: Electrical characterization

Automatic IV characterization



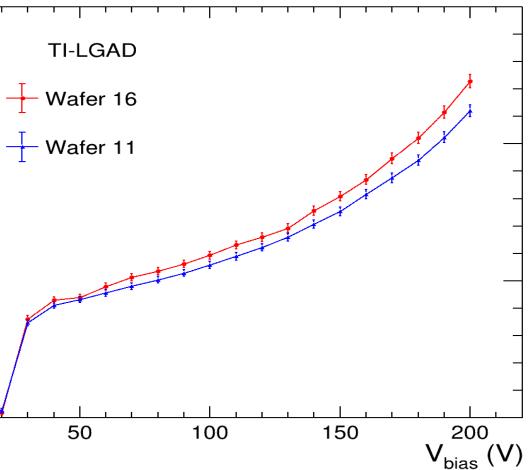




Dark current ~ 10 pA/mm²

2x2 pixels
1.3 mm² pixels
ATLAS/CMS Timing Layer

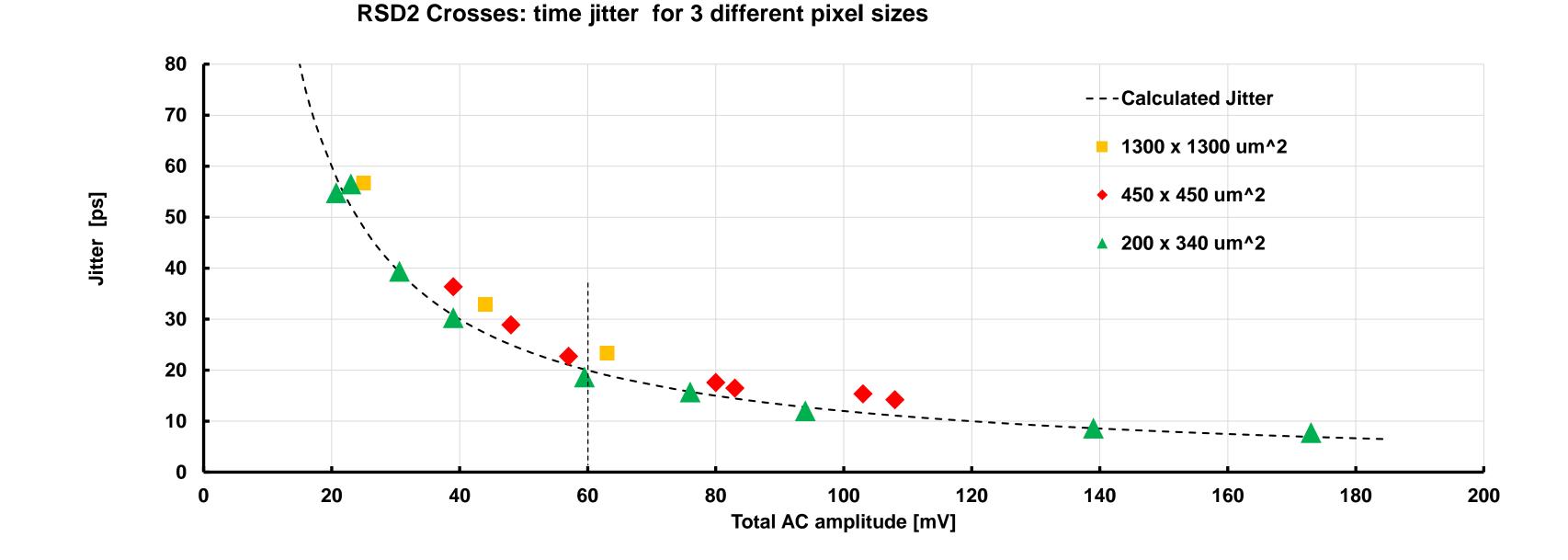
GAIN



- TCT Setup with IR Laser
- 200V and RT

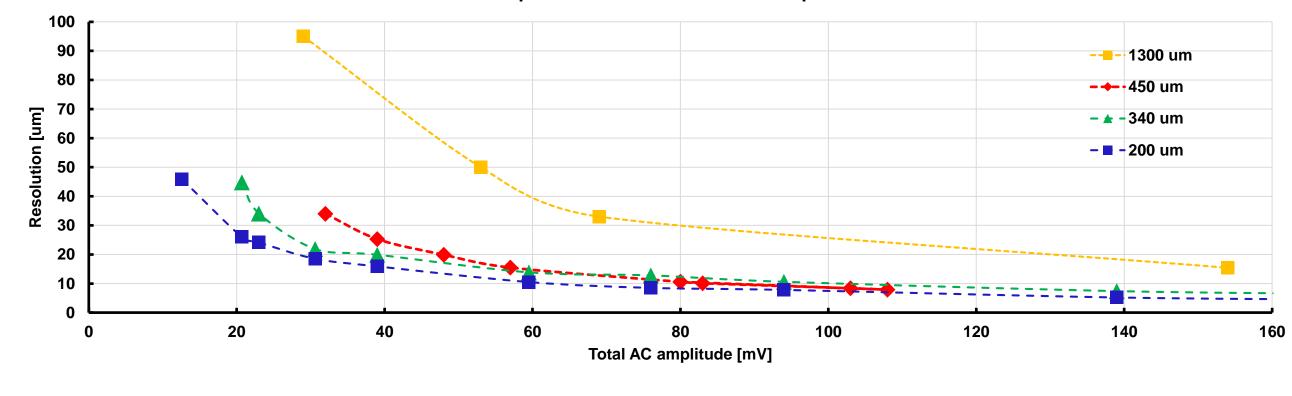
$$Gain = \frac{Q_{LGAD}}{Q_{PiN}}$$

Temporal resolution



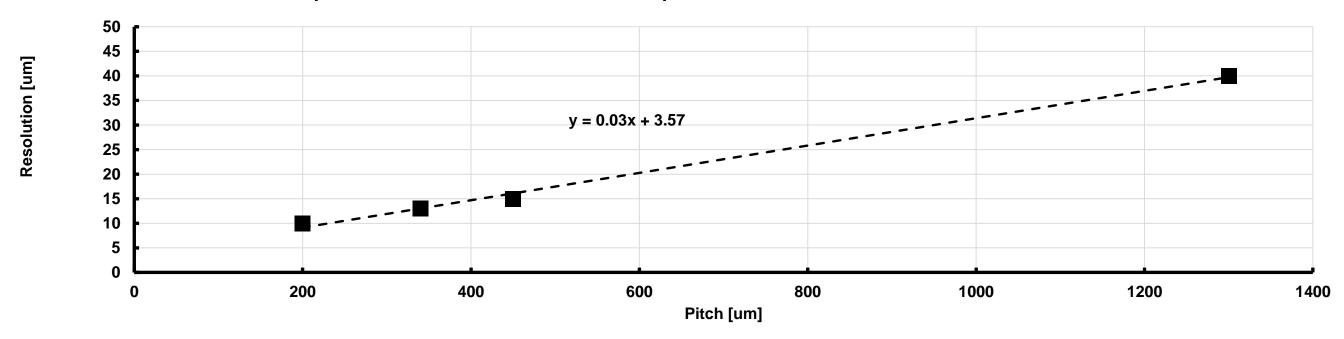
The temporal resolution does not depend on the pize size, only on the total amplitude. (total amplitude = sum of the amplitudes of the 4 read-out electrodes at the pixel corner)

Spatial resolution as a function of the signal amplitude for 4 pitch sizes



RSD2 crosses: spatial resolution for 4 different pitch sizes

RSD2 crosses: spatial resolution when the total AC amplitude = 60 mV



Executive summary: the resolution is 3% of the pixel size

(total amplitude = sum of the amplitudes of the 4 read-out electrodes at the pixel corner)

Latest FBK RSD production RSD2

The key feature of RSD2 is to design the electrodes to have as little metal as possible and to maximize sharing among the read-out pads at the corner of

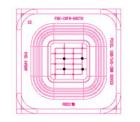
the pixel **RSD2 crosse overall result:**

- Spatial resolution ~ 3% pitch size
- Temporal resolution ~ 35 ps, regardless of pitch size

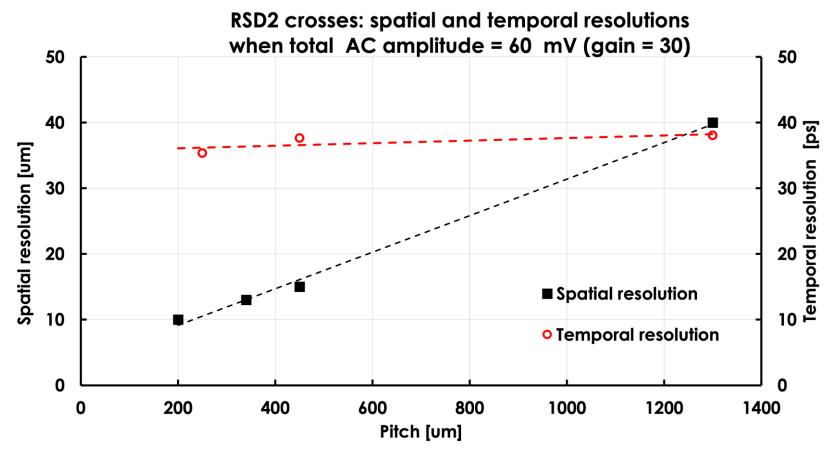
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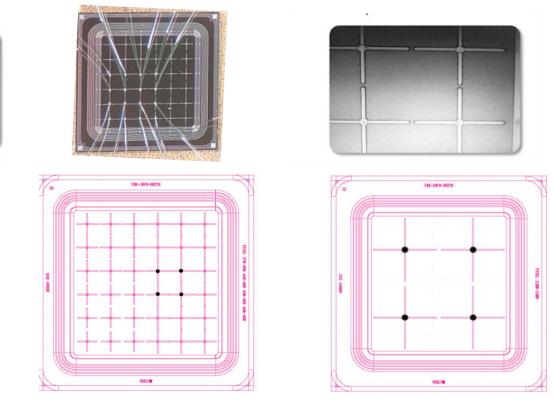
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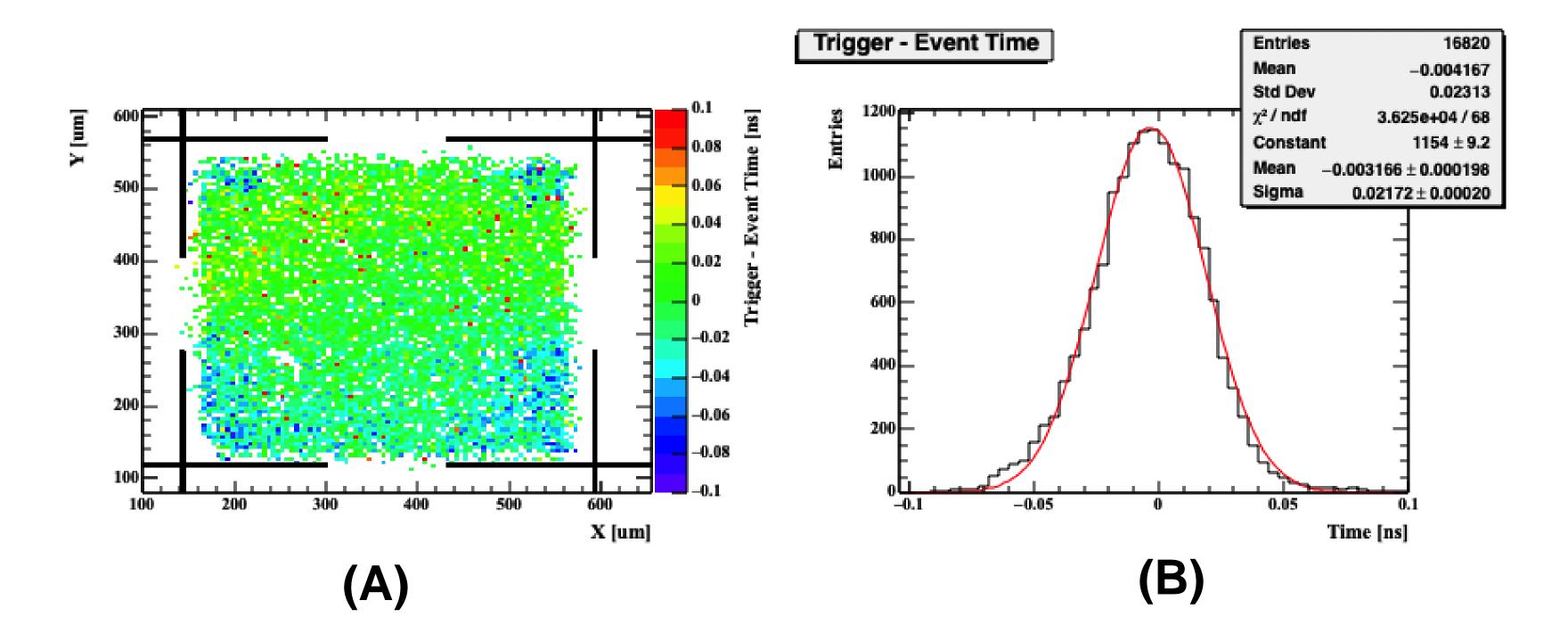








Example of uniformity in the time resolution over the whole pa



Plot obtained by shooting laser shots (TCT system) over the whole pixel surface and comparing the